## Notice of References Cited Application/Control No. 10/665,312 Examiner Quoc A. Tran Applicant(s)/Patent Under Reexamination STUPLE ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2003/0030645 A1	02-2003	Ribak et al.	345/581
	В	US-			
	C	US-			·
	D	US-			
	E	US-			
	F	US-			
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## FOREIGN PATENT DOCUMENTS

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